

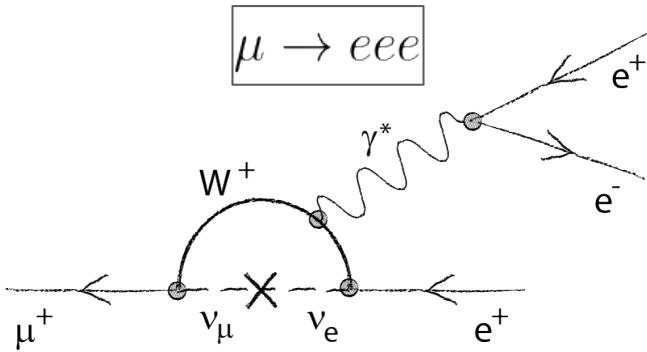
Mu3e vertex detector prototyping

Thomas Theodor Rudzki for the Mu3e collaboration
Universität Heidelberg - Physikalisches Institut

DPG-Frühjahrstagung, Internet, 16. März 2021



The Mu3e experiment

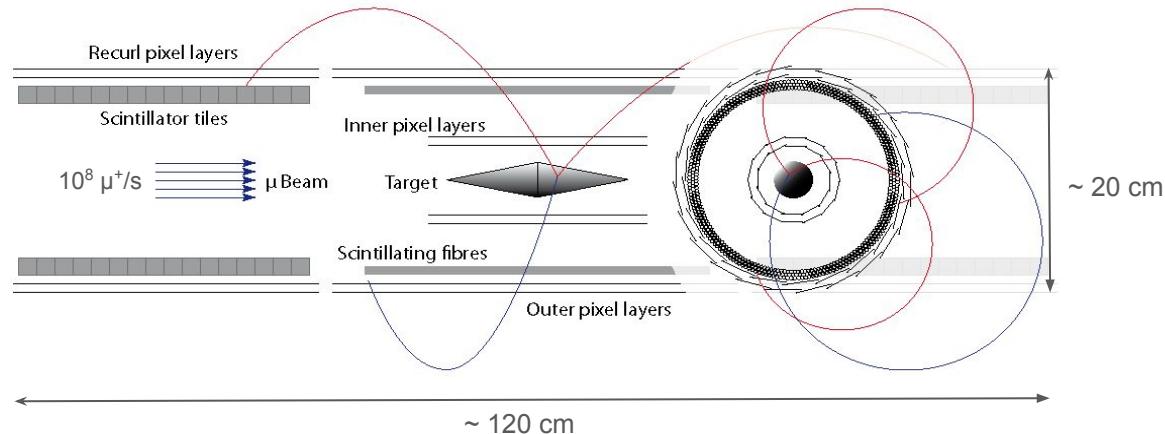


Standard Model branching ratio:

$$\mathcal{B}(\mu \rightarrow eee) \leq 1 \cdot 10^{-54}$$

Current limit (SINDRUM, 1988):

$$\mathcal{B}(\mu \rightarrow eee) < 1 \cdot 10^{-12}$$



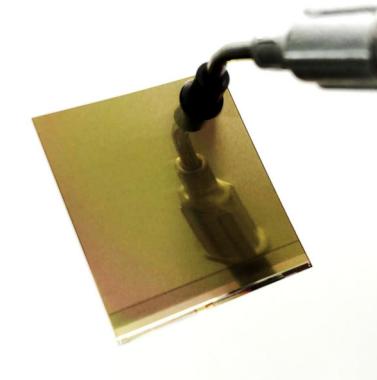
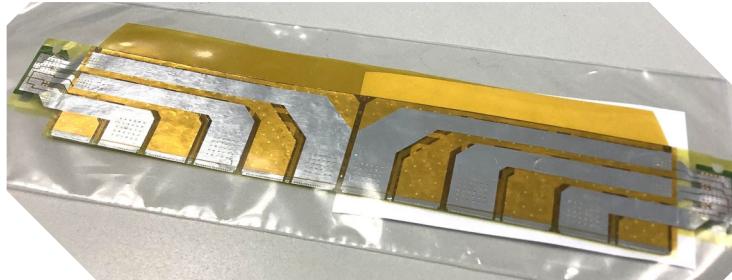
Aimed final single-event sensitivity :

$$\mathcal{B}(\mu \rightarrow eee) \leq 1 \cdot 10^{-16}$$



The Mu3e experiment

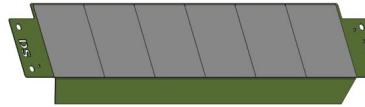
- Muon decay at rest
 - Positron/electron momenta < 53 MeV/c
- Background dominated by multiple Coulomb scattering
 - Reduction of material budget
- Ultra-thin sensors (50 μm HV-MAPS, $X/X_0 = 0.054 \%$)
- High-density interconnects (HDI) as only support structure (polyimide + Al, 50 μm , $X/X_0 = 0.061 \%$)
- Gaseous helium as coolant (low Z)



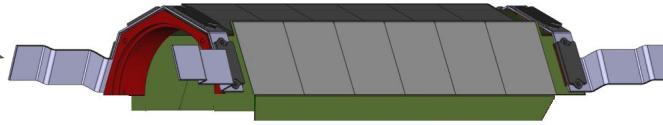


Vertex detector geometry

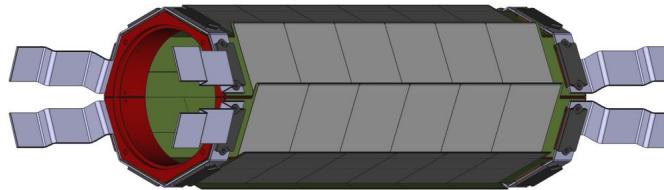
- 2 inner layers
 - 8/10 ladders each
 - 6 chips per ladder
- Target surrounded by inner layers
- Support (red) attached to beam pipes
- Electrical connections via flexprints
- Helium inlets on the faces



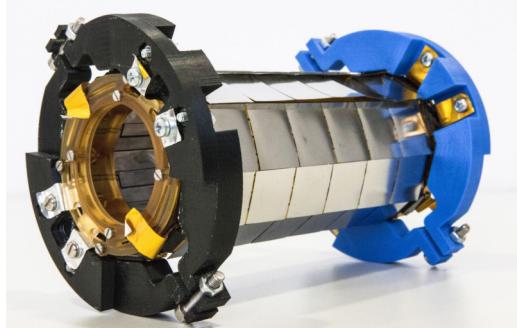
Ladder



Module



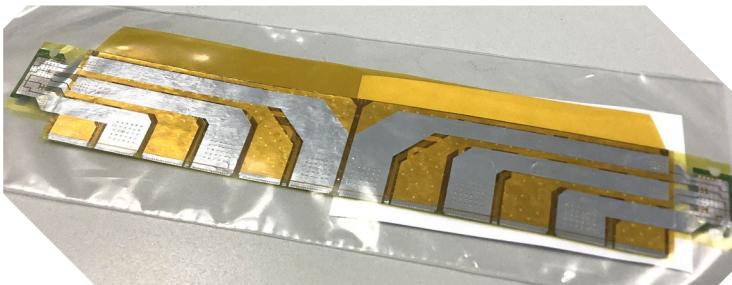
Layer





Prototyping

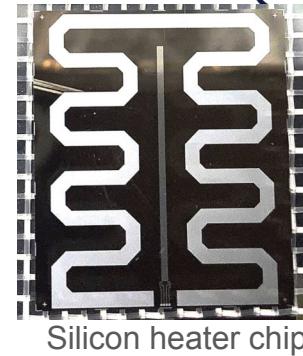
- Step to final materials/precision using silicon heater chips
- Silicon chips as active heating components
- HDI as support structure
- Electrical connection via spTAB
- Goals:
 - Verify feasibility of all working steps
 - Establish quality assurance procedure for final production



HDI for silicon heater chips



spTAB bond



Silicon heater chip



Layer stack of LTU hdi

Ladder construction

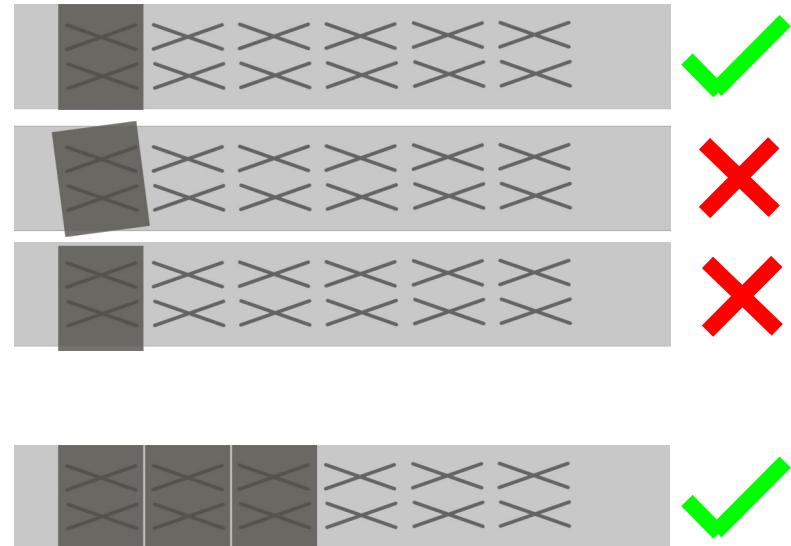
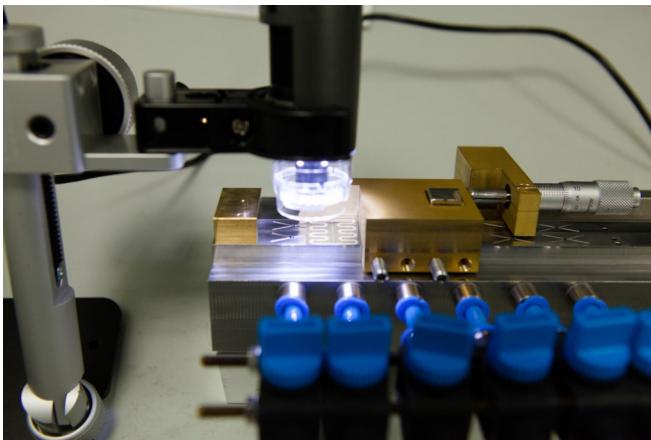
- Placing 6x sensors in a row
- Apply glue
- Position hdi
- Putting weights on ladder + curing glue
- Bonding electrical connections





Sensor placement

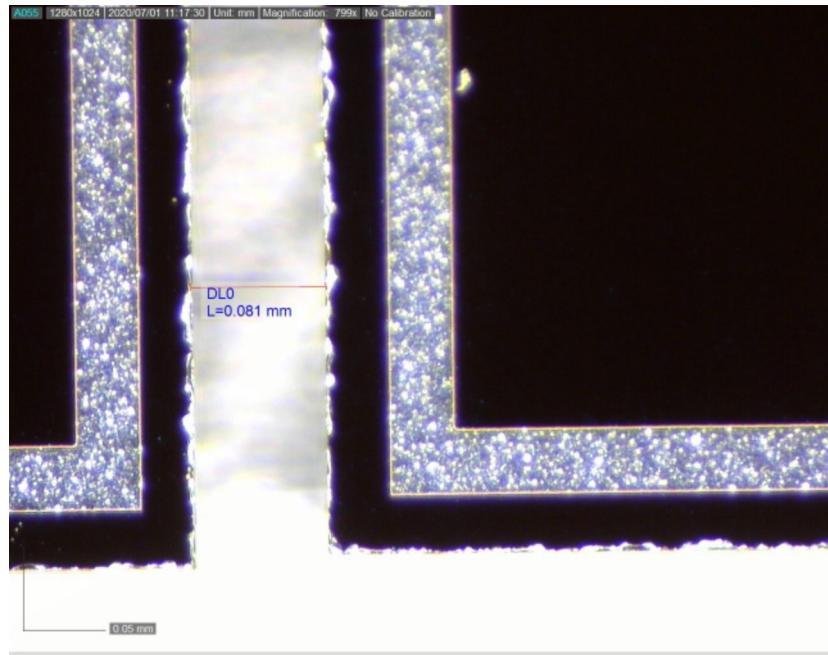
- Placement precision of $5 \mu\text{m}$ (chip-to-chip distance)
- Gap between chips: $80 \pm 5 \mu\text{m}$ (Si heater)
 $40 \pm 5 \mu\text{m}$ (MuPix)
- Resulting of slight size differences
- Chip confinement while placing on chuck necessary





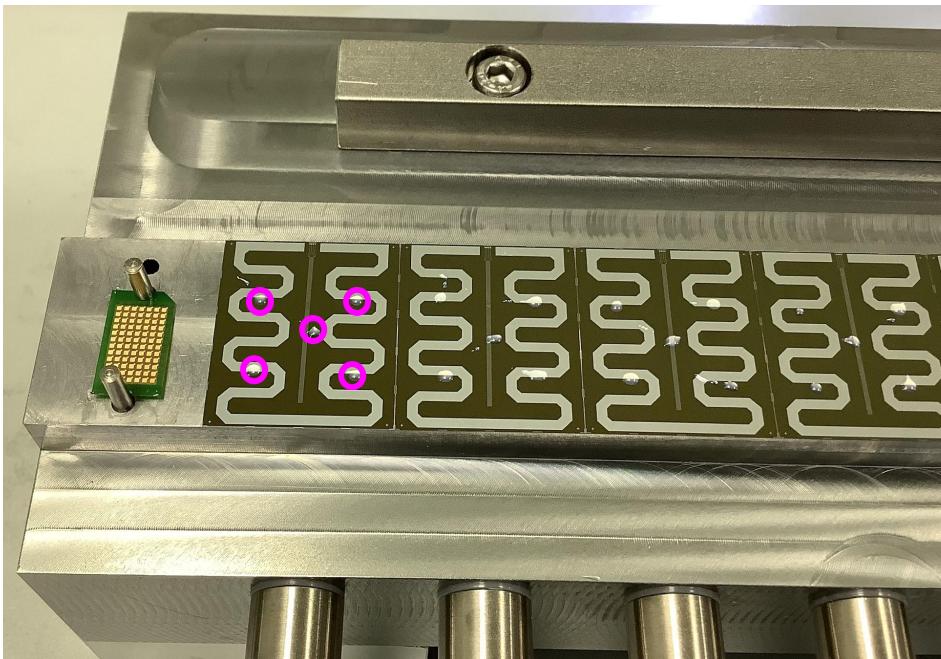
Sensor placement

- Manual placement with micrometer screw
- Measurement of distances via digital microscope
- Optical resolution of $1.5 \mu\text{m}$
- Chip placement with $\sigma < 5 \mu\text{m}$ well under control



Gluing

- Gluing by applying small glue dots using a toothpick
- Measured thickness of
 - Heaters
 - HDI
 - Heaters + HDI after gluing
- Obtain “glue thickness maps”

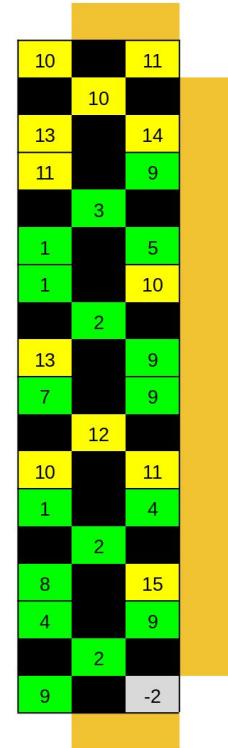
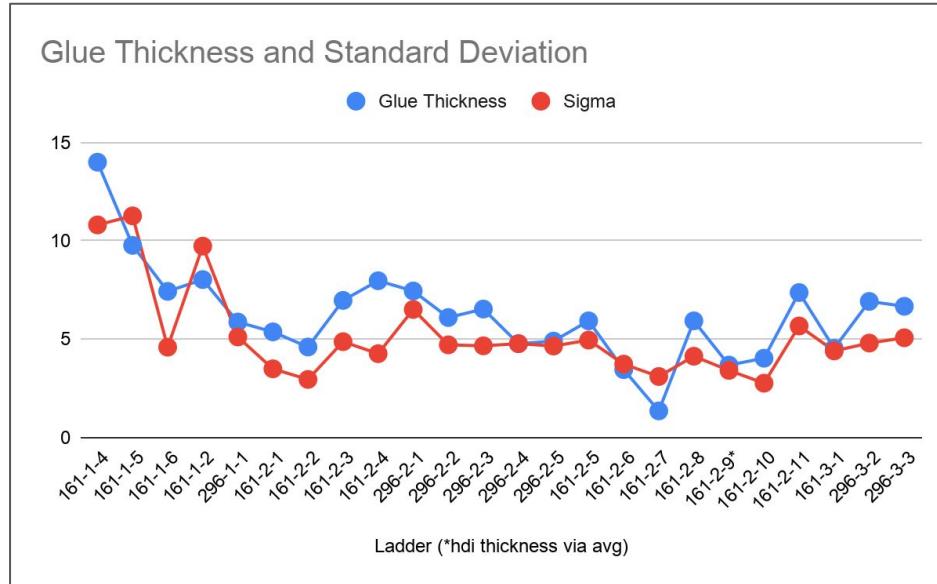


5-glue-dots pattern on each sensors



Gluing

- Gluing by applying small glue dots using a toothpick
- Measured thickness of
 - Heaters
 - HDI
 - Heaters + HDI after gluing
- Obtain “glue thickness maps”
- Little material budget:
 - ~ 5 µm aimed thickness
 - After some practice
glue thickness @ 5-7 µm
 - Satisfying results



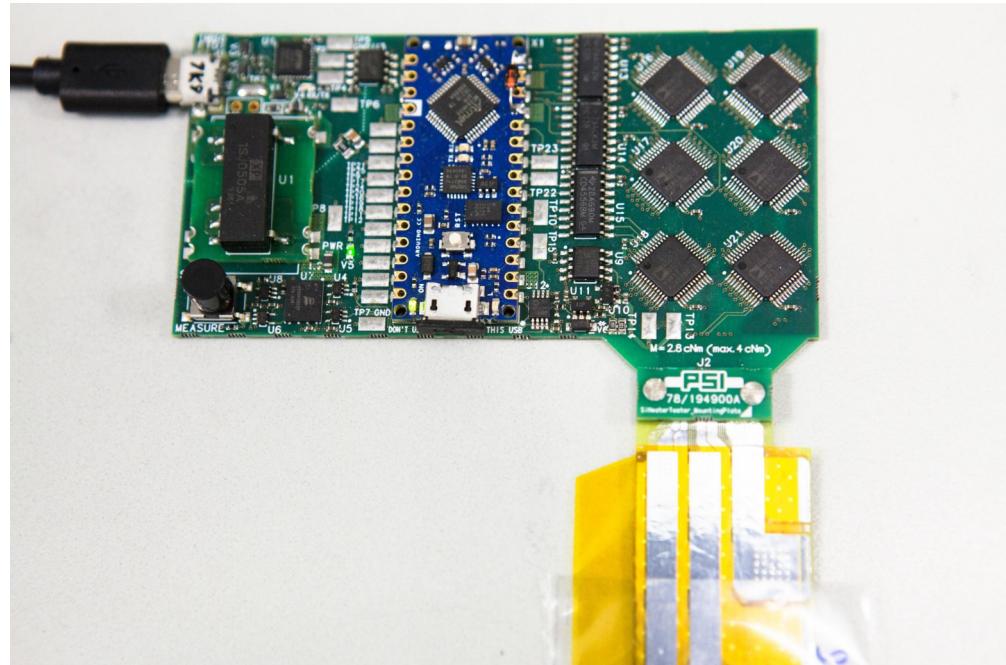


Si heater tester

- Arduino based test board
- Checks all connection within 1 second
- Rebonding if necessary



spTAB bond



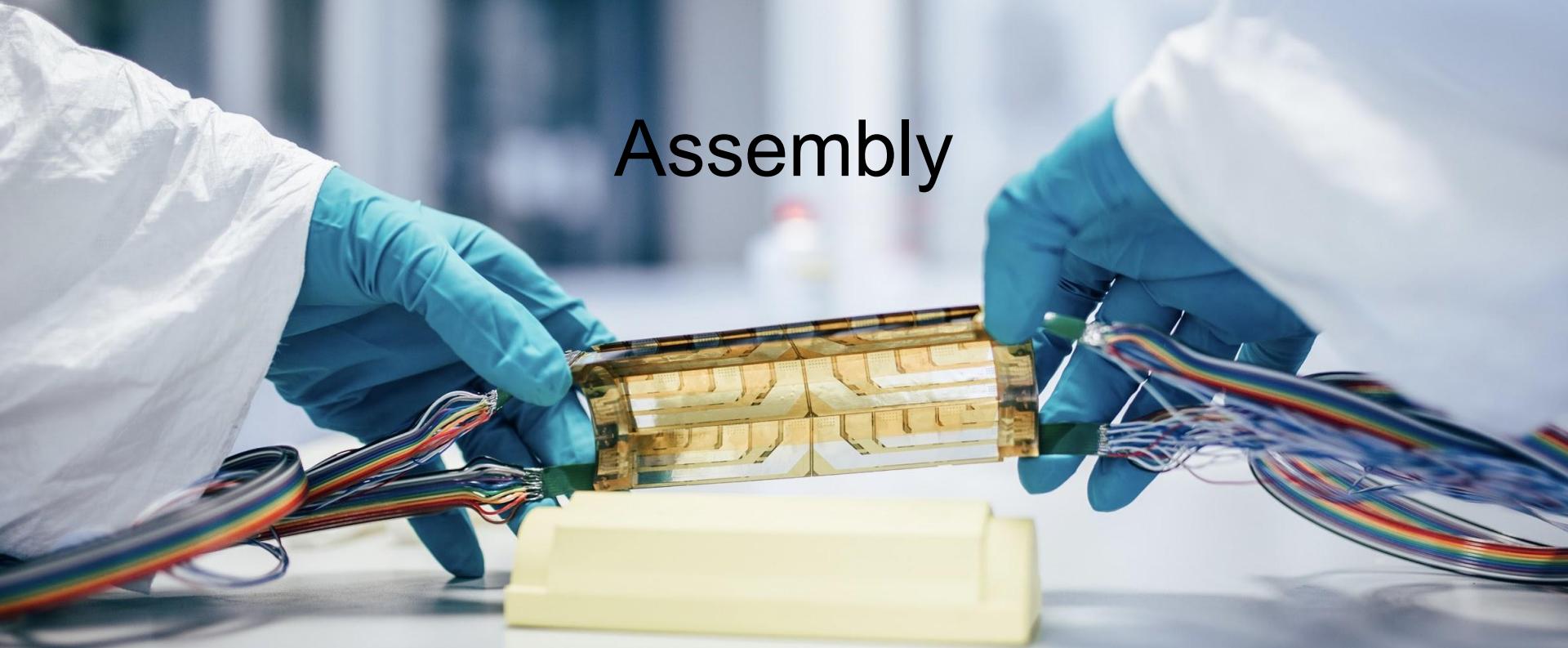
ladder	General remarks	thickness	distances	bad bonds
161-1-3	Some Si broke off at 1 sensor (maybe usable)	No Q&A	~ 100 µm	2x Power #1
161-1-4	Good to use	$\mu = 14 \mu\text{m}$	~ 100 µm	Temp. #6
161-1-5	Two broken sensors	$\mu = 10 \mu\text{m}$	~ 80 µm	Not tested
161-1-6	Good to use	$\mu = 7 \mu\text{m}$	~ 80 µm	-
161-1-2	Good to use	$\mu = 8 \mu\text{m}$	~ 80 µm	-
161-2-1	Good to use	$\mu = 5 \mu\text{m}$	~ 80 µm	-
161-2-2			~ 80 µm	-
161-2-3			~ 80 µm	-
161-2-4	#		~ 80 µm	-
161-2-5			~ 80 µm	Temp. #4 (#37)
161-2-6			~ 80 µm	-
161-2-7			~ 80 µm	-
161-2-8	Goo		~ 80 µm	T.. #3 & #6 on chip
161-2-9	#		~ 80 µm	Power #6
161-2-10			~ 80 µm	Temp. #6
161-2-11			~ 80 µm	T. bonds offset large
161-3-1	Good to use		~ 80 µm	
296-1-1	Good to use	$\mu = 6 \mu\text{m}$	~ 80 µm	-
296-2-1	Two broken sensors	$\mu = 7 \mu\text{m}$	~ 80 µm	Not tested
296-2-2	Good to use	$\mu = 6 \mu\text{m}$	~ 80 µm	-
296-2-3	Good to use	$\mu = 7 \mu\text{m}$	~ 80 µm	-
296-2-4	#6 broken (might be usable)	$\mu = 8 \mu\text{m}$	~ 80 µm	Temp. #6
296-2-5	Interposer Flex not correctly glued	$\mu = 5 \mu\text{m}$	~ 80 µm	Not tested
296-3-1	Good to use	Not tested	~ 80 µm	Temp. #6

Yield:

75 % of ladders used

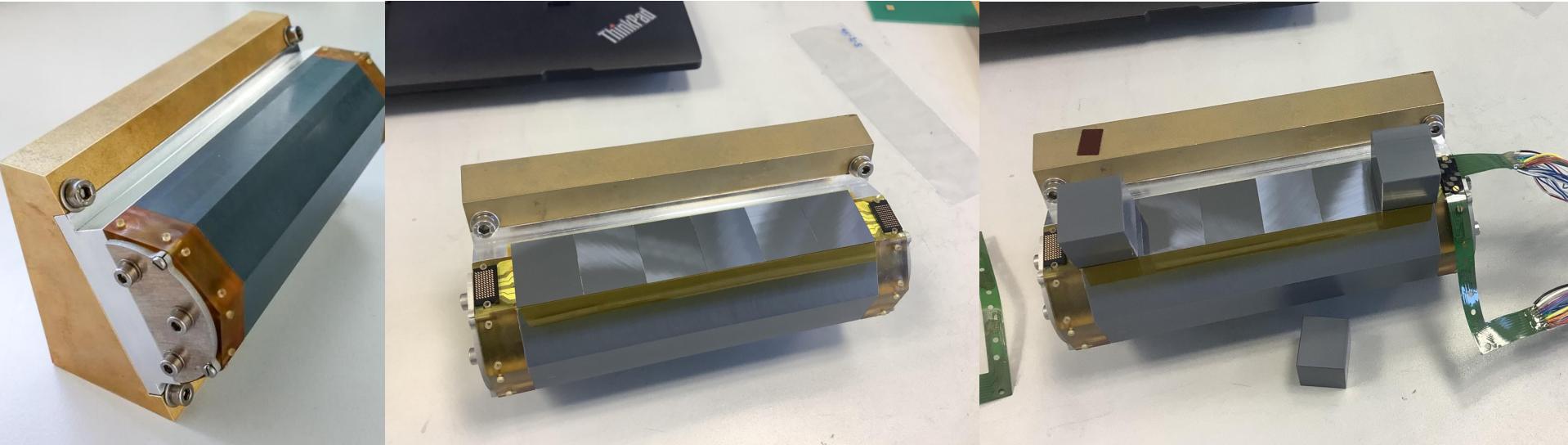
67 % would have been used for final tracker

Assembly



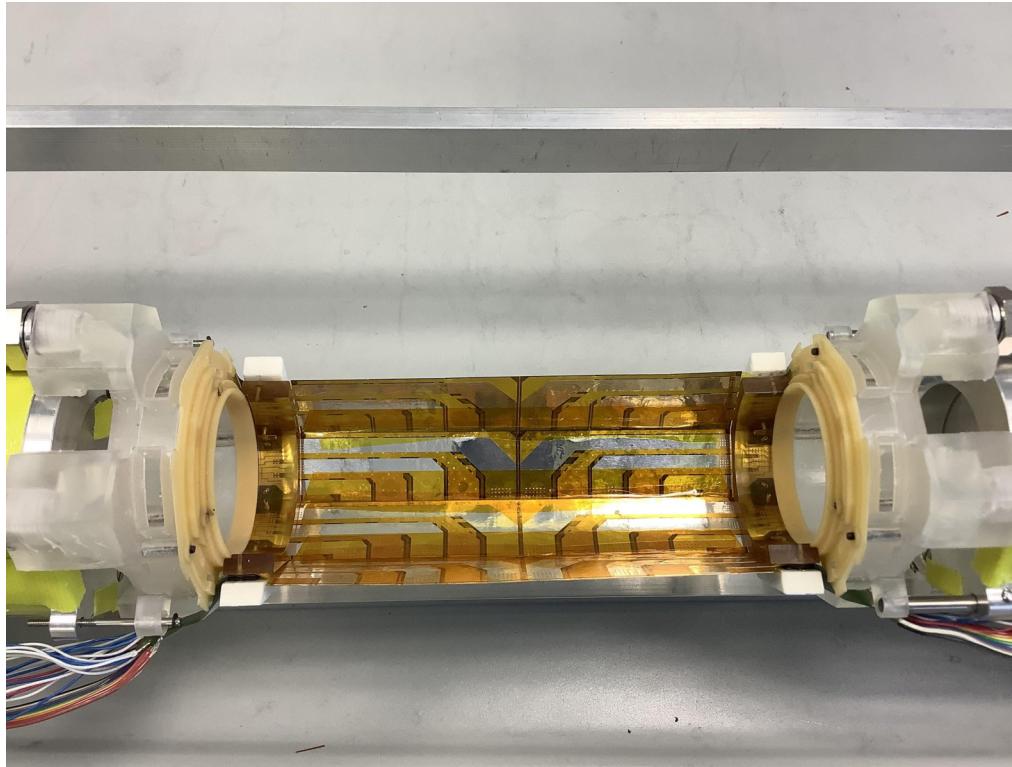


Final module construction



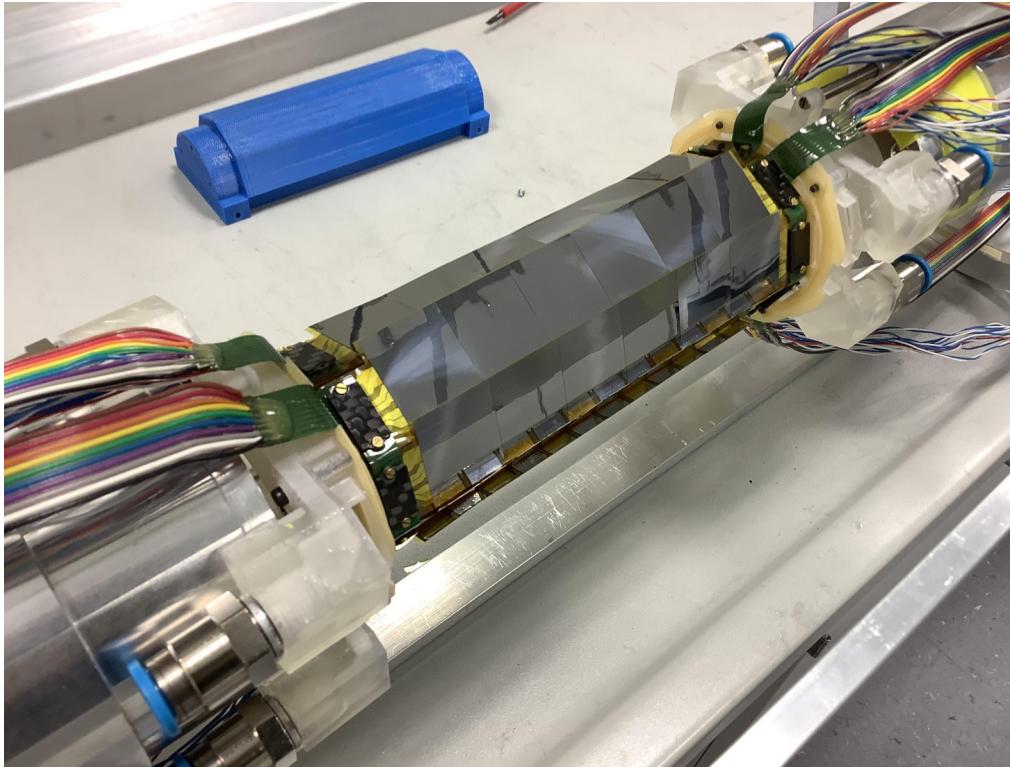


Construction of the vertex detector





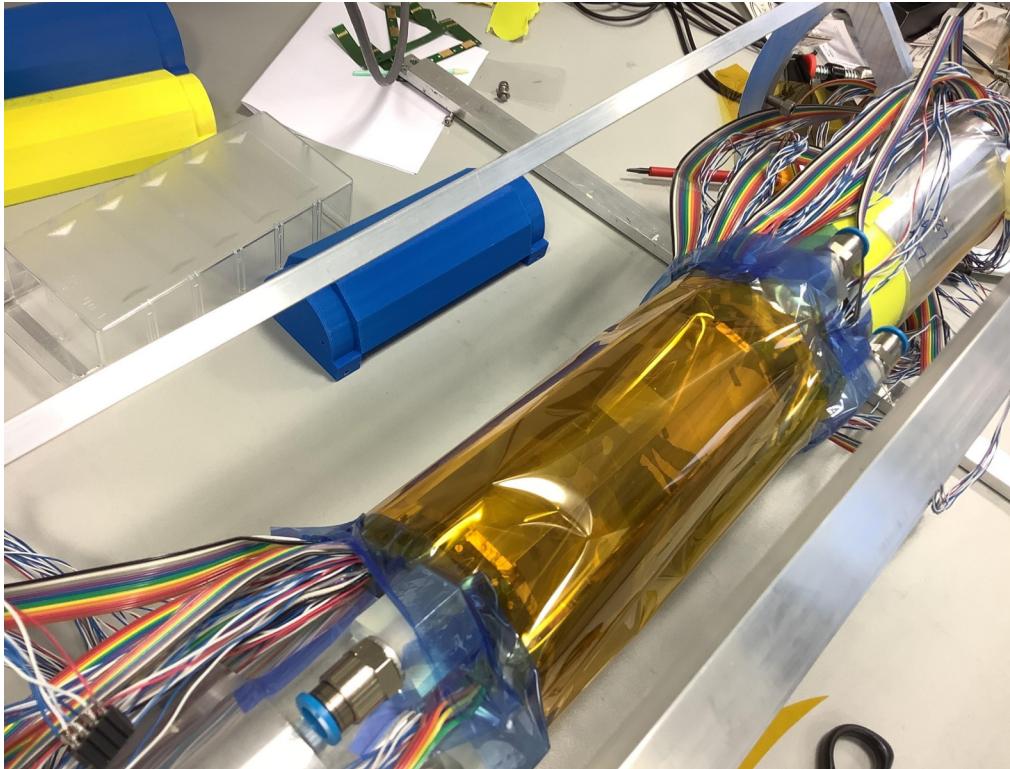
Construction of the vertex detector



Thomas Rudzki – Universität Heidelberg



Construction of the vertex detector



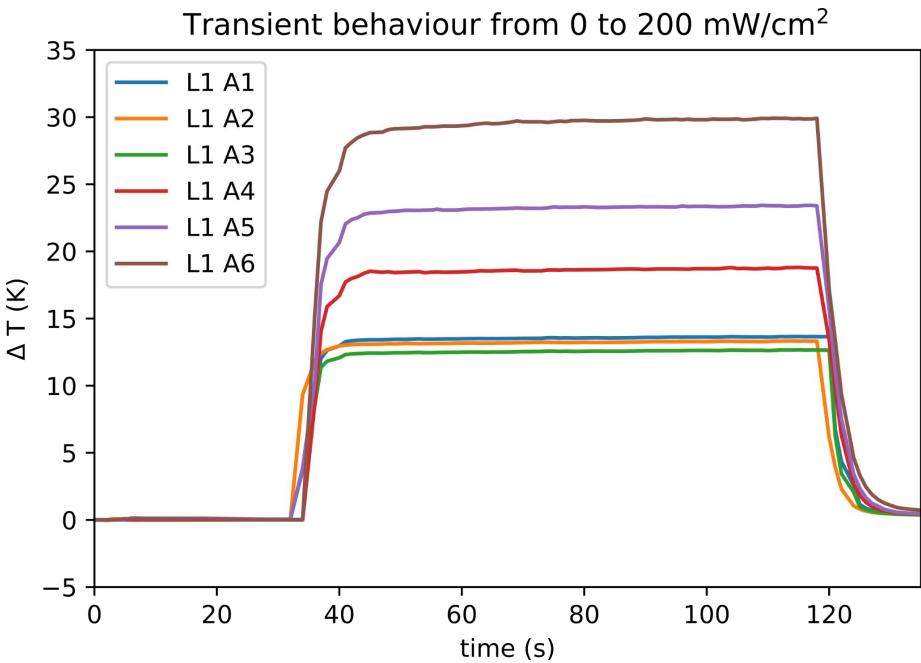
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Cooling results

Thermodynamic behavior of the mockup:

- Nominal heat load of 200 mW/cm^2
- Temperature measured for 6 sensor on one inner ladders
- Equilibrium reached in seconds
- Maximum allowed temperature is 70°C
- Maximum $\Delta T \sim 30 \text{ K}$
(foreseen inlet temperature $\sim 5^\circ\text{C}$)

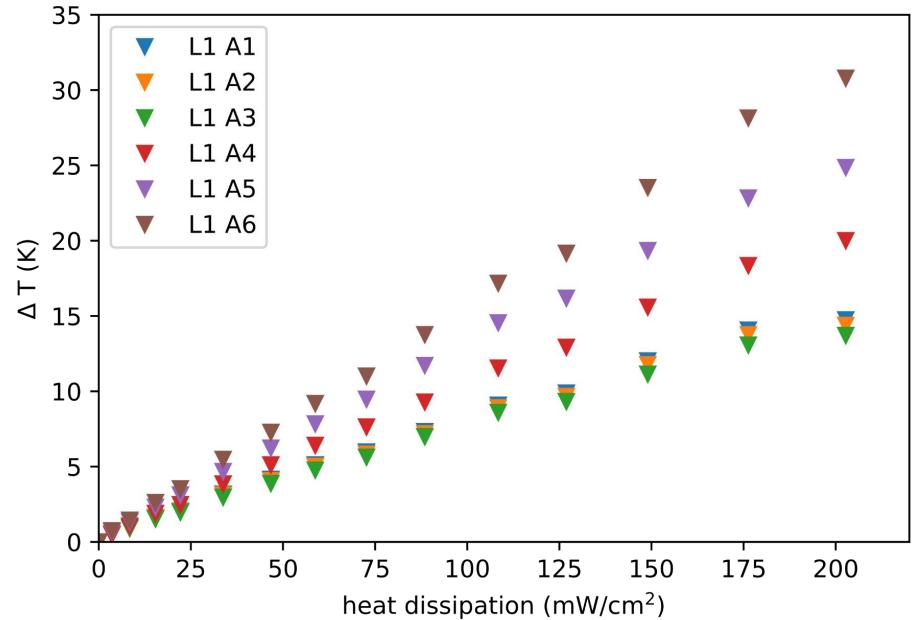




Cooling results

Measurement of temperature-to-power relation

- Temperature difference linearly depending on heat dissipation
- Expected $\Delta T < 70$ K for 400 mW/cm 2 (conservative limit)
- Cooling concept works ✓



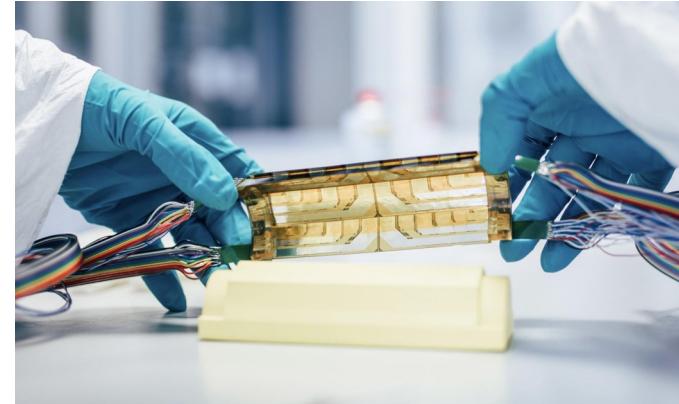


Summary & Outlook

- Feasibility of construction & functionality the cooling concept verified
- Mounting procedure ready for production in 2021/2022
- 1st ladders with 6 chips using PCBs will be tested in May 2021
- 1st ladders with 6 chips on HDI expected in summer 2021
- Mass production of final MuPix11 ladders in early 2022



6-chip PCB for test run (summer 2021)



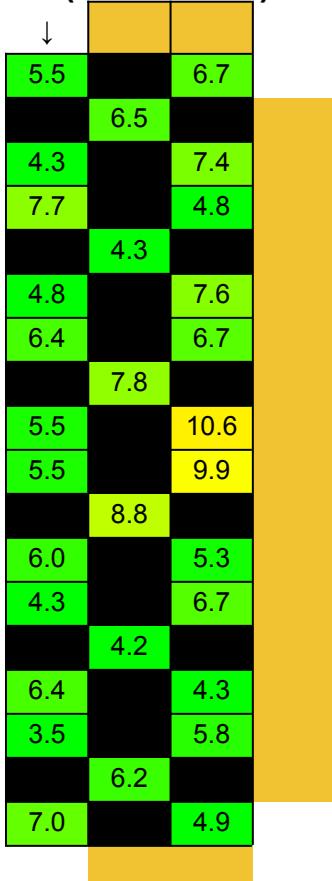


Backup

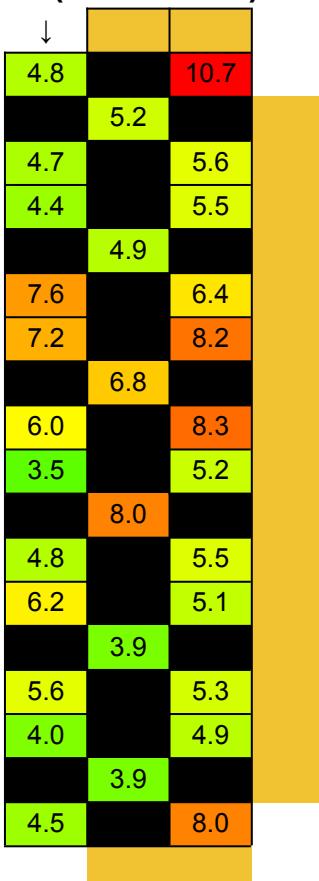
Systematic effects of tooling?



Average Thickness
(all ladders)



Sigma Thickness
(all ladders)



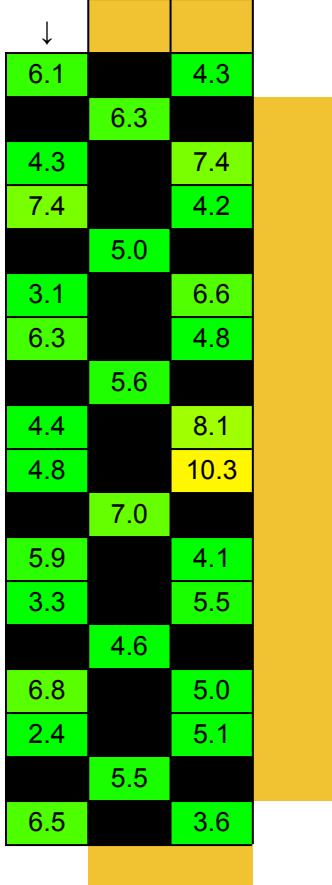
Overall average:
 $6.2 \pm 1.7 \mu\text{m}$

- Local differences mainly from fluctuations

Systematic effects of tooling?

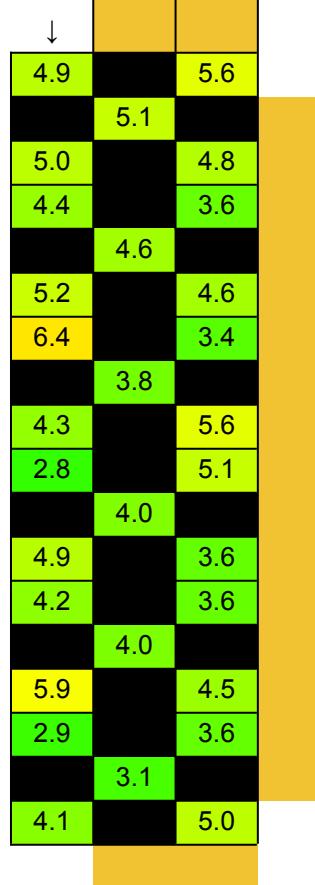


Average Thickness
(excluded first 3 ladders)



Overall average:
 $5.5 \pm 1.7 \mu\text{m}$

Sigma Thickness
(excluded first 3 ladders)



- Local differences mainly from fluctuations
- E.g. removing only first 3 ladders changes pictures
- $\sigma_{\text{glue spots}} = 4.7 \mu\text{m}$
- Results are satisfying :-)